

# LP2995 **DDR Termination Regulator General Description**

The LP2995 linear regulator is designed to meet the JEDEC SSTL-2 and SSTL-3 specifications for termination of DDR-SDRAM. The device contains a high-speed operational amplifier to provide excellent response to load transients. The output stage prevents shoot through while delivering 1.5A continuous current and transient peaks up to 3A in the application as required for DDR-SDRAM termination. The LP2995 also incorporates a  $V_{SENSE}$  pin to provide superior load regulation and a  $V_{\text{REF}}$  output as a reference for the chipset and DDR DIMMS.

50uf

#### Patents Pending

#### **Features**

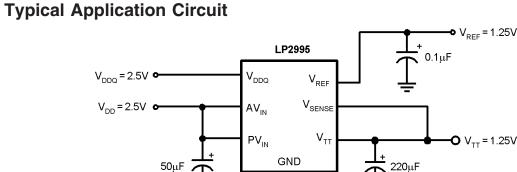
- Low output voltage offset
- Works with +5v, +3.3v and 2.5v rails
- Source and sink current
- Low external component count
- No external resistors required
- Linear topology
- Available in SO-8, PSOP-8 or LLP-16 packages

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Low cost and easy to use

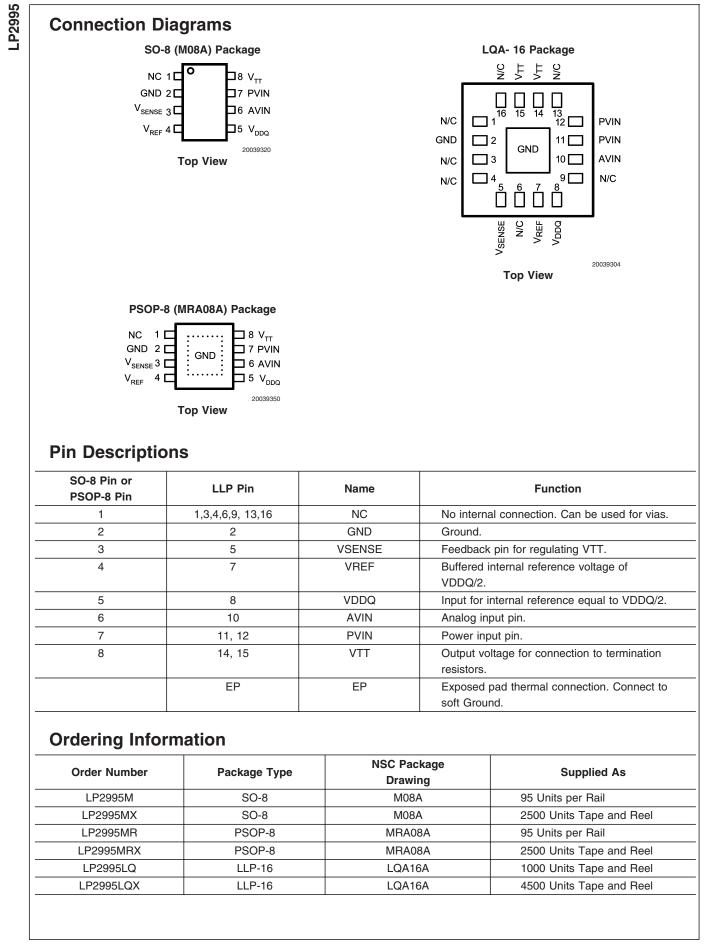
### Applications

- DDR Termination Voltage
- SSTL-2
- SSTL-3



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LP2995 DDR Termination Regulator



## Absolute Maximum Ratings (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/ Distributors for availability and specifications.

LLP-16 Thermal Resistance  $(\theta_{IA})$ 51°C/W Lead Temperature (Soldering, 10 sec) ESD Rating (Note 7)

LP2995

260°C

1kV

PVIN, AVIN, VDDQ to GND	-0.3V to +6V
Storage Temp. Range	–65°C to +150°C
Junction Temperature	150°C
PSOP-8 Thermal Resistance ( $\theta_{JA}$ )	43°C/W
SO-8 Thermal Resistance $(\theta_{JA})$	151°C/W

# **Operating Range**

Junction Temp. Range (Note 5)	0°C to +125°C
AVIN to GND	2.2V to 5.5V
PVIN to GND	2.2V to AVIN

**Electrical Characteristics** Specifications with standard typeface are for T<sub>J</sub> = 25°C and limits in **boldface** type apply over the full Operating Temperature Range ( $T_{J} = 0^{\circ}C$  to +125°C). Unless otherwise specified, AVIN = PVIN = 2.5V, VDDQ = 2.5V (Note 6).

Symbol	Parameter	Conditions	Min	Тур	Max	Units
V <sub>REF</sub>	V <sub>REF</sub> Voltage	I <sub>REF_OUT</sub> = 0mA	1.21	1.235	1.26	V
VOS <sub>VTT</sub>	V <sub>TT</sub> Output Voltage Offset	I <sub>OUT</sub> = 0A (Note 2)	-15 <b>-20</b>	0	15 <b>20</b>	mV
$\Delta V_{TT}/V_{TT}$	Load Regulation (Note 3)	$I_{OUT} = 0$ to 1.5A $I_{OUT} = 0$ to -1.5A		0.5 -0.5		%
Z <sub>VREF</sub>	V <sub>REF</sub> Output Impedance	I <sub>REF</sub> = -5μA to +5μA		5		kΩ
Z <sub>VDDQ</sub>	VDDQ Input Impedance			100		kΩ
l <sub>q</sub>	Quiescent Current	I <sub>OUT</sub> = 0A (Note 4)		250	400	μA

Note 1: Absolute maximum ratings indicate limits beyond which damage to the device may occur. Operating range indicates conditions for which the device is intended to be functional, but does not guarantee specific performance limits. For guaranteed specifications and test conditions see Electrical Characteristics. The guaranteed specifications apply only for the test conditions listed. Some performance characteristics may degrade when the device is not operated under the listed test conditions.

Note 2: V<sub>TT</sub> offset is the voltage measurement defined as V<sub>TT</sub> subtracted from V<sub>BEE</sub>.

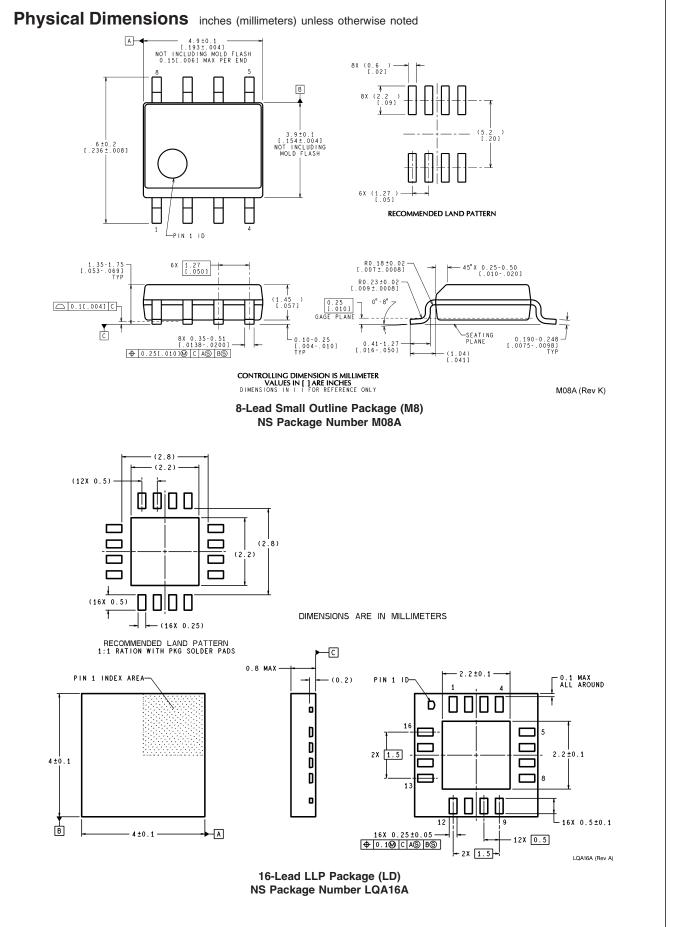
**Note 3:** Load regulation is tested by using a 10ms current pulse and measuring  $V_{TT}$ .

Note 4: Quiescent current defined as the current flow into AVIN.

Note 5: At elevated temperatures, devices must be derated based on thermal resistance. The device in the SO-8 package must be derated at  $\theta_{JA} = 151^{\circ}$  C/W junction to ambient with no heat sink. The device in the LLP-16 must be derated at  $\theta_{JA} = 51^{\circ}$  C/W junction to ambient.

Note 6: Limits are 100% production tested at 25°C. Limits over the operating temperature range are guaranteed through correlation using Statistical Quality Control (SQC) methods. The limits are used to calculate National's Average Outgoing Quality Level (AOQL).

Note 7: The human body model is a 100pF capacitor discharged through a  $1.5k\Omega$  resistor into each pin.



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